

The listing of claims will replace all prior versions, and listings, of claims in this application:

Listing of Claims:

1 1. (Original) Method enabling a command to switch the measure mode to be
2 entered in a dimension-measuring column provided with a probe tip,
3 wherein said command to switch the measure mode is entered by only making
4 use of the position of said probe tip.

1 2. (Original) The method of claim 1, wherein said command to switch the
2 measure mode is entered by pressing the probe tip against a piece to be measured during a
3 time interval greater than a predetermined value.

1 3. (Original) The method of claim 2, wherein a measurement of the probing point
2 is effected when the probe tip is pressed against said piece to be measured during a time
3 interval shorter than said predetermined value.

1 4. (Currently Amended) Method enabling a command to switch the measure
2 mode to be entered in a dimension-measuring column provided with a probe tip,
3 wherein said command to switch the measure mode is entered by only making
4 use of the position of said probe tip,
5 wherein said command to switch the measure mode is entered by pressing the
6 probe tip against a piece to be measured during a time interval greater than a predetermined
7 value,

8 ~~The method of claims 2,~~ wherein said mode switch command enables said
9 measuring column to pass into a mode to search for the turn-back point of said piece to be
10 measured.

1 5. (Original) The method of claim 4, wherein the status of the display of said
2 measuring column is modified following said mode switch so as to indicate the status of the
3 pressing force of said probe tip against said piece to be measured.

1 6. (Original) The method of claim 5, wherein said pressing force is indicated by
2 means of a bar graph.

1 7. (Original) The method of claim 4, wherein said measuring column remains in
2 said turn-back point search mode as long as a sufficient pressing force is exerted by the probe
3 tip against the piece to be measured, said turn-back point being determined automatically
4 within the trajectory covered by said probe tip in said search mode.

1 8. (Original) The method of claim 7, wherein said measurement of the turn-back
2 point is not taken into account when said pressing force exceeds a predefined admissible
3 interval.

1 9. (Original) The method of claim 4, wherein said turn-back point is determined
2 as being the extreme of the vertical trajectory covered by said probe tip in said search mode.

1 10. (Original) The method of claim 4, wherein said turn-back point is validated
2 only if the derivative of the probe tip's vertical position is close to zero at said extreme.

1 11. (Original) The method of claim 4, wherein the area around the turn-back
2 point is scanned several times in succession in opposite directions without the pressing force
3 being released,
4 the measured turn-back point being validated only when the vertical position of
5 several thereof finds itself within a determined interval.

1 12. (Original) The method of claim 1, wherein an aural and/or visual signal is
2 emitted during a said mode switch.

1 13. (Currently Amended) The method of claim + 12, wherein said command to
2 switch the measure mode is entered by pressing the probe tip against a piece to be measured
3 during a time interval greater than a predetermined value.

1 14. (Original) Method enabling a command to switch the measure mode to be
2 entered in a height-measuring column provided with a probe tip,
3 said height-measuring column having a plurality of measure modes for
4 measuring a plurality of different parameters of a piece,
5 wherein said command to switch the measure mode is entered by pressing said
6 probe tip against a piece to be measured,
7 wherein said height-measuring column remains in said measure mode as long as
8 a sufficient pressing force is exerted by the probe tip against the piece to be measured.

1 15. (Original) Method for entering a command in a dimension-measuring column
2 provided with a probe tip,
3 said command enabling said measuring column to pass into a mode to search
4 for the turn-back point of said piece to be measured,
5 said command being entered only by pressing said probe tip against a piece to
6 be measured during a time interval greater than a predetermined value.

1 16. (Original) The method of claim 15, wherein a measurement of the probing
2 point is effected when the probe tip is pressed against said piece to be measured during a time
3 interval shorter than said predetermined value.

1 17. (Original) Dimension-measuring column, comprising:
2 a probe tip designed for being brought into contact with the piece to be
3 measured,
4 a displacement mechanism of said probe tip,
5 a measuring and displaying system that allows the position of said probe tip to
6 be determined and displayed, said measuring and displaying system being able to function
7 according to several distinct modes,
8 wherein at least one of said measure modes can be selected by acting on the
9 position of the probe tip, without any other handling operating being necessary.

1 18. (Original) The measuring column of claim 17, wherein said measure mode can
2 be selected by pressing the probe tip against the piece to be measured during a time interval
3 greater than a predetermined value.

1 19. (Original) The measuring column of claim 18, wherein the measurement of the
2 probing point is effected when the probe tip is pressed against said piece to be measured
3 during a time interval shorter than said predetermined value.

1 20. (Currently Amended) Dimension-measuring column, comprising:
2 a probe tip designed for being brought into contact with the piece to be
3 measured,
4 a displacement mechanism of said probe tip,
5 a measuring and displaying system that allows the position of said probe tip to
6 be determined and displayed, said measuring and displaying system being able to function
7 according to several distinct modes,
8 wherein at least one of said measure modes can be selected by acting on the
9 position of the probe tip, without any other handling operating being necessary,
10 wherein said measure mode can be selected by pressing the probe tip against
11 the piece to be measured during a time interval greater than a predetermined value,
12 wherein the measurement of the probing point is effected when the probe tip is
13 pressed against said piece to be measured during a time interval shorter than said
14 predetermined value,
15 ~~The measuring column of claim 19, wherein said measure mode is a~~
16 mode to search for the turn-back point of said piece to be measured.

1 21. (Original) The measuring column of claim 20, comprising a display whose
2 status is modified following said mode switch so as to indicate the status of the pressing force
3 of said probe tip against said piece to be measured.

1 22. (Original) The measuring column of claim 21, wherein said display enables a
2 bar graph capable of indicating said pressing force.

1 23. (Original) The measuring column of claim 22, wherein it remains in turn-back
2 point search mode as long as a sufficient pressing force is exerted by the probe tip against the
3 piece to be measured, said turn-back point being determined automatically within the
4 trajectory covered by said probe tip in search mode.

1 24. (Original) The measuring column of claim 23, wherein said measurement of
2 the turn-back point is not taken into account when said pressing force exceeds a predefined
3 admissible interval.

1 25. (Original) The measuring column of claim 24, wherein said turn-back point is
2 determined as being the extreme of the vertical trajectory covered by said probe tip in said
3 search mode.

1 26. (Original) The measuring column of one of the claims 25, wherein said turn-
2 back point is validated only if the derivative of the probe tip's vertical position is close to zero
3 at said extreme.

1 27. (Original) The measuring column of one of the claims 26, wherein, when the
2 area around the turn-back point is scanned several times in succession in opposite directions
3 without the pressing force being released, the measured turn-back point is validated only when
4 the vertical position of several thereof finds itself within a determined interval.

1 28. (Original) The measuring column of claim 17, comprising a loudspeaker to
2 emit a sound signal during said mode switch.

1 (29) (Original) Computer data carrier comprising a command program for
2 measuring and displaying system in a dimension-measuring column, said program enabling the
3 position of the probe tip of said measuring column to be determined and displayed, said
4 program being capable of making said measuring and displaying system function according to
5 several distinct modes,

6 wherein said program enables another of said measure modes to be selected by
7 acting on the position of the probe tip.

1 30. (Previously Added) Method enabling a command to switch a measure mode to
2 be entered in a dimensional-measuring column provided with a probe tip,

3 wherein said command to switch the measure mode is entered by means of deliberate
4 handling operations of a height-command crank.

1 31. (Previously Added) Method according to claim 30, wherein said command to
2 switch the measure mode enables said dimension-measuring column to pass into a mode to
3 search for a turn-back point of said piece to be measured.

1 32. (Previously Added) Method according to claim 30, wherein said command to
2 switch the measure mode results in modifying the measuring accuracy and/or resolution.

1 33. (Previously Added) The method according to claim 30, wherein a status of the
2 display of said dimension-measuring column is modified following said command to switch the
3 measure mode so as to indicated the status of a pressing force of said probe tip against a piece
4 to be measured.

1 34. (Previously Added) The method of claim 30, wherein said command to switch
2 the measure mode is entered by pressing said probe tip against a piece to be measured during a
3 time interval shorter than a predetermined value.

1 35. (Previously Added) Dimension-measuring column, comprising:
2 a probe tip designed for being brought into contact with a piece to be measured,
3 a height-command crank for displacing said probe tip,
4 a measuring and displaying system that allows the position of said probe tip to be
5 determined and displayed,
6 wherein a command to switch the measure mode is entered by means of deliberate
7 handling operations of the height-command crank.

1 36. (Previously Added) The dimension-measuring column of claim 35, wherein said
2 command to switch the measure mode enables a measuring column to pass into a mode to
3 search for a turn-back point of said piece to be measured.

1 37. (Previously Added) The dimension-measuring column of claim 35, wherein said
2 mode switch command results in modifying the measuring accuracy and/or resolution.

1 38. (New) The method of claim 4, wherein said command to switch the measure
2 mode is entered by pressing the probe tip against a piece to be measured during a time interval
3 greater than a predetermined value.

1 39. (New) The method of claim 38, wherein a measurement of the probing point is
2 effected when the probe tip is pressed against said piece to be measured during a time interval
3 shorter than said predetermined value.

1 40. (New) The method of claim 4, wherein an aural and/or visual signal is emitted
2 during a said mode switch.

1 41. (New) The measuring column of claim 20, wherein said measure mode can be
2 selected by pressing the probe tip against the piece to be measured during a time interval
3 greater than a predetermined value.

1 42. (New) The measuring column of claim 41, wherein the measurement of the
2 probing point is effected when the probe tip is pressed against said piece to be measured
3 during a time interval shorter than said predetermined value.

1 43. (New) The measuring column of claim 20, comprising a loudspeaker to emit a
2 sound signal during said mode switch.
